Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
09/704,898	ABI-NASSIF ET AL.		
Examiner	Art Unit		
CHUONG T. HO	2616		

SEARCHED				
Class	Subclass	Date	Examiner	
370	412	02/27/07	CH	
370	310			
370	೭32			
370	231			
370	23.5			
370	33Z			
370	395.72		ļ	
370	468			
370	395.4			
370	230			
370	H50			
370	H66			
370	452			
370	395.21			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
WEST (Text rearch,	02/27/07	CH	
Class rearch)			
EAST			
STN			
IEEE	<u> </u>		
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